

Specifications

Drawing No.	UKY1C-H1-19002-00[37] 1/10
Issued Date.	Jan,7,2019

TO: Digi-Key

Note: In case of specification change, KYOCERA Part Number also will be changed.

Product Name	Quartz Crystal
Product Model	CX2016DB
Frequency	26000kHz
Customer Part Number	-
Customer Specification Number	-
KYOCERA Part Number	CX2016DB26000D0FSST4
Remarks	Pb-Free, RoHS Compliant, MSL 1 AEC-Q200 Compliant

Customer Acceptance

Accept Signature	Approved Date	
	Department	
	Person in charge	

Seller

KYOCERA Corporation

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Manufacturer

Corporate Electronic Components Group
Crystal Components Division

Design Department	Quality Assurance	Approved by	Checked by	Issued by
KYOCERA Corporation Crystal Units Design Engineering Yamagata Section Crystal Product Division	W. Muraoka	Y. Takahashi	T. Nitoube	Y. Kikuchi

Revision History

Rev.No.	Description of revise	Date	Approved by	Checked by	Issued by
1	First Edition	Jan,7,2019	Y. Takahashi	T. Nitoube	Y. Kikuchi

1. APPLICATION

This specification sheet is applied to quartz crystal "CX2016DB26000D0FSST4"

2. KYOCERA PART NUMBER

CX2016DB26000D0FSST4

3. RATINGS

Items	SYMB.	Rating	Unit	Remarks
Operating Temperature	Topr	-40 to +125	°C	
Storage Temperature range	Tstg	-40 to +150	°C	

4. CHARACTERISTICS

ELECTRICAL CHARACTERISTICS

Items	Electrical Specification					Test Condition	Remarks
	SYMB.	Min	Typ.	Max	Unit		
Mode of Vibration		Fundamental					
Nominal Frequency	F0		26		MHz		
Nominal Temperature	T _{NOM}		25		°C		
Load Capacitance	CL		8.0		pF		
Frequency Tolerance	df/F	-10.0		+10.0	PPM	+25±3°C	
Frequency Temperature characteristics	df/F	-50.0		+50.0		-40 to +125°C	
Frequency Aging Rate		-20.0		+20.0		10 years	+25±3°C
Equivalent Series Resistance	ESR			60	Ω		
Motional Capacitance	C1	-15%	1.69	+15%	fF		
Shunt Capacitance	C0	-15%	0.62	+15%	pF		
Drive Level	Pd	0.01		100	μW		
Insulation Resistance	IR	500			MΩ	100V(DC)	

5. Measurement Condition

5.1 Frequency measurement

Measuring instrument : IEC PI-Network Test Fixture
 Load Capacitance : 8.0pF
 Drive Level : 10μW

5.2 Equivalent series resistance (ESR) measurement

Measuring instrument : IEC PI-Network Test Fixture
 Load Capacitance : Series
 Drive Level : 10μW

6. Parts Numbering Guide

CX2016DB 26000 D0 F S S T 4
A B C D E F G

A : Series(Crystal Units)

B : Frequency 26000kHz

C : Load Capacitance

D0 : 8.0pF

D : Frequency Stability

F : $\pm 10 \times 10^{-6}$

E : Operating Temp. Range

S : -40 to +125°C

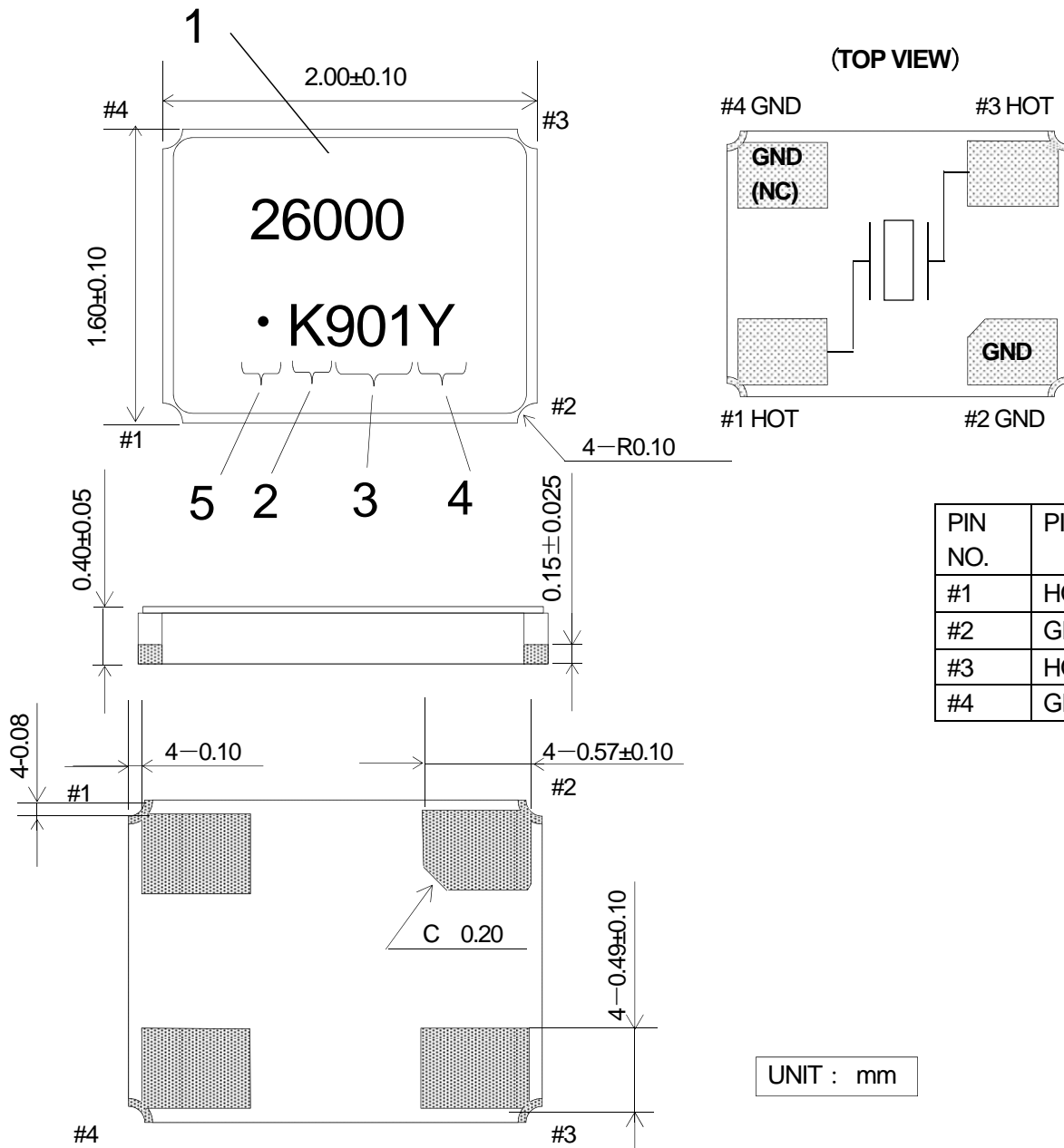
F : Frequency Temp. Stability

S : $\pm 50 \times 10^{-6}$

G : Suffix for Individual Requirements

7. APPEARANCES, PHYSICAL DIMENSION

OUTLINE DIMENSION (not to scale)



PIN NO.	PIN Layout
#1	HOT
#2	GND
#3	HOT
#4	GND

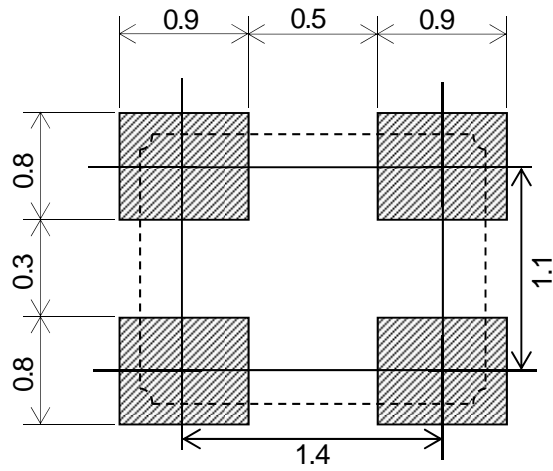
UNIT : mm

MARKING

- Nominal Frequency Move the number of maximum indication beams of the frequency to five digits, and omit less than kHz.
 - Identification [K] mark is surely 1Pin direction.
 - Date Code Year · · · LAST 1 DIGIT of YEAR AND WEEK
(Ex) Jan, 01, 2019 → 901
 - Manufacturing Location
Y · · · Japan (Yamagata)
Z · · · Japan (Shiga Yohkaichi)
- 4 . No.1 pin is expressed.

※The font of marking is reference.

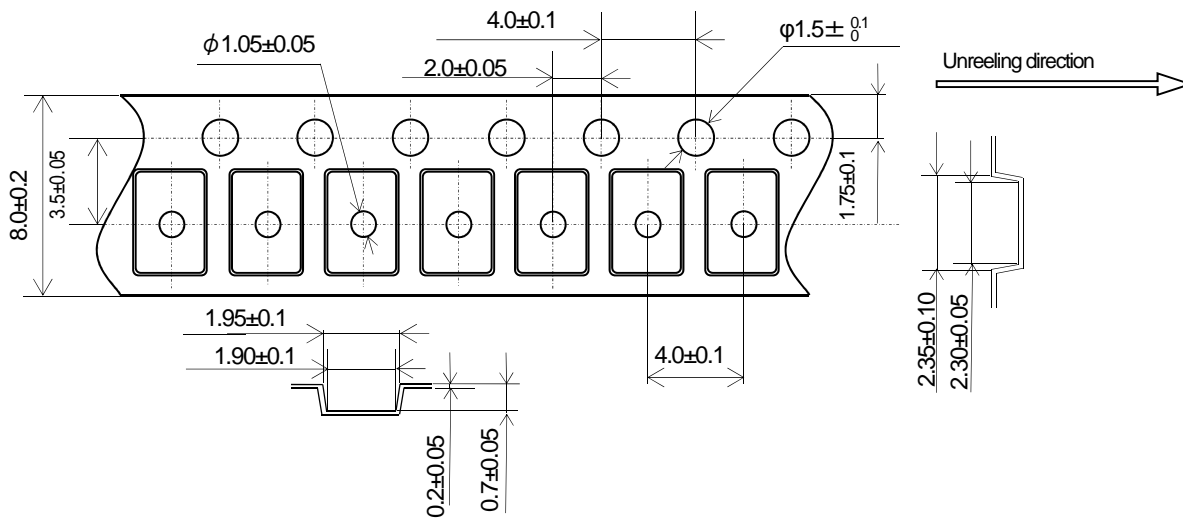
KYOCERA Corporation

8. RECOMMENDED LAND PATTERN (not to scale)

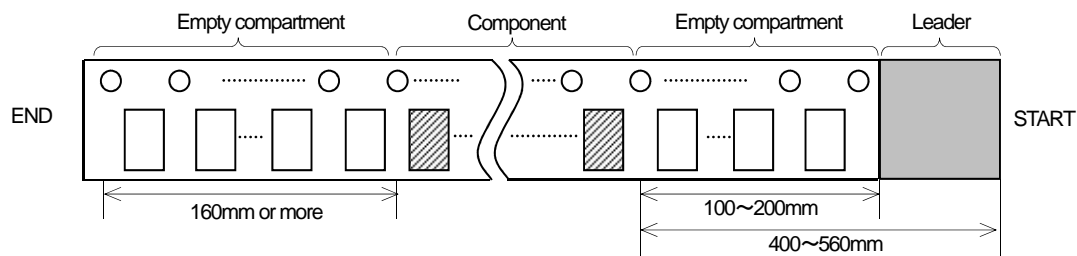
UNIT : mm

9. TAPING&REEL

9-1.Dimensions



9-2.Leader and trailer tape

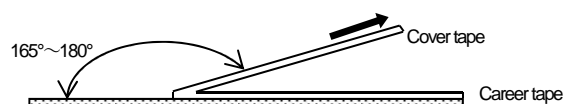


9-3.Direction (The direction shall be seen from the top cover tape side)

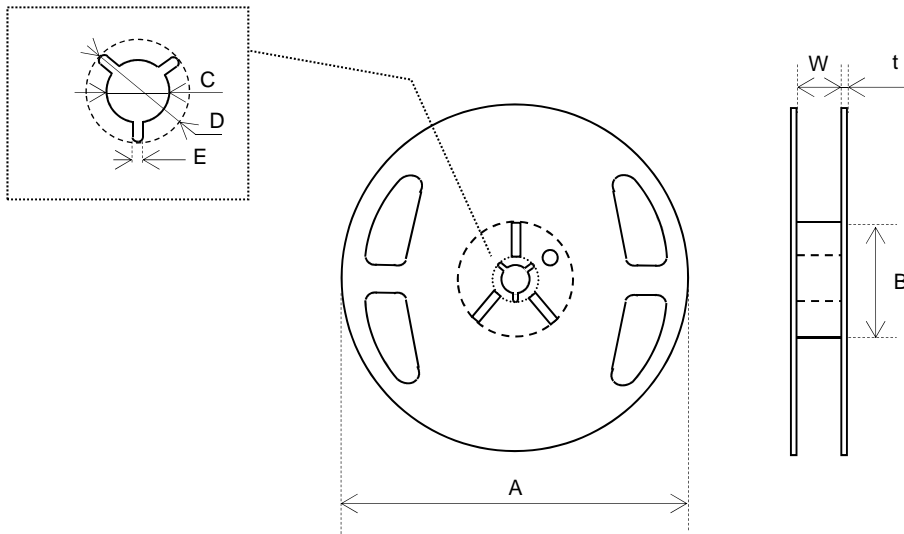


9-4.Specification

1. Material of the carrier tape shall be polystyrene or A—PET (ESD).
2. Material of the seal tape shall be polyester (ESD).
3. The seal tape shall not cover the sprocket holes. And not protrude from the carrier tape.
4. Tensile strength of the tape: 10N or more.
5. The R of the corner without designation is 0.2RMAX.
6. The alignment between centers of the cavity and sprocket hole shall be 0.05mm or less.
7. Cumulative pitch tolerance of "P₀" shall be ± 0.2 mm at 10 pitches.
8. Suppose that it unifies as shown in the above-mentioned figure to the directivity of printing in an embossing tape.
9. Peeling force of the seal tape: 0.1 to 1.0N.
10. The component can fall headlong naturally from taping in the environment, such dry conditions, when this components were transferred to, cover was removed and the component was moved upside down.



9-5.Reel Specification



In the case of $\phi 180$ Reel (3,000 pcs max, every 1,000 pcs)

Symbol	A	B	C	D
Dimension	$\phi 180 +0/-3$	$\phi 60 +1/-0$	$\phi 13 \pm 0.2$	$\phi 21 \pm 0.8$
Symbol	E	W	t	
Dimension	2.0 ± 0.5	9 ± 1	2.0 ± 0.5	

(Unit : mm)

In the case of $\phi 330$ Reel (12,000 pcs max, every 1,000 pcs)

Symbol	A	B	C	D
Dimension	$\phi 330 \pm 2.0$	$\phi 100 \pm 1.0$	$\phi 13 \pm 0.2$	$\phi 21 \pm 0.8$
Symbol	E	W	t	
Dimension	2.0 ± 0.5	9.5 ± 0.5	2.2 ± 0.1	

(Unit : mm)

10. ENVIRONMENTAL AND MECHANICAL CHARACTERISTICS :

(Reference: AEC-Q200 Rev. D. The solder used by examination is hereafter set to Sn-3Ag-0.5Cu.)

After following test, Frequency applies to each item and CI, $\pm 20\%$ or 5 Ω of large value.

No	Stress	Reference	Additional Requirements
10.1	High Temperature Exposure (Storage)	MIL-STD-202 Method 108	1000 hrs. at rated operating temperature (e.g. 85°C part can be stored for 1000 hrs at 85°C. Same applies for 125°C). Unpowered. Measurement at 24 \pm 4 hours after test conclusion.
10.2	Temperature Cycling	JESD22 Method JA-104	1000 cycles (-40°C to 125°C) Note: If 85°C part the 1000 cycles will be at that temperature rating. Measurement at 24 \pm 4 hours after test conclusion. 30min maximum dwell time at each temperature extreme. 1 min. maximum transition time.
10.3	Biased Humidity	MIL-STD- 202 Method 103	1000 hours 85°C/85%RH. Rated VDD applied with 1 MW and inverter in parallel, 2X crystal CL capacitors between each crystal leg and GND. Measurement at 24 \pm 4 hours after test conclusion.
10.4	Operational Life	MIL-STD- 202 Method 108	Note: 1000 hrs @ 125°C. If 85°C part will be tested at that temperature. Rated VDD applied with 1 MW and inverter in parallel, 2X crystal CL capacitors between each crystal leg and GND. Measurement at 24 \pm 4 hours after test conclusion.
10.5	Terminal Strength (Leaded)	MIL-STD- 202 Method 211	Test leaded device lead integrity only. Conditions: A (227 g), C (227 g).
10.6	Resistance to Solvents	MIL-STD- 202 Method 215	Note: Also aqueous wash chemical - OKEM clean or equivalent. Do not use banned solvents.
10.7	Mechanical Shock	MIL-STD-202 Method 213	Figure 1 of Method 213. Condition C
10.8	Vibration	MIL-STD-202 Method 204	5g's for 20 minutes 12 cycles each of 3 orientations. Note: Use 8"X5" PCB .031" thick with 7 secure points on one 8" side and 2 secure points on corners of opposite sides. Parts mounted within 2" from any secure point. Test from 10-2000 Hz.
10.9	Resistance to Soldering Heat	MIL-STD-202 Method 210	Condition B No pre-heat of samples. Note: Single Wave solder - Procedure 1 with solder within 1.5 mm of device body for Leaded. Procedure 1 except 230°C and immerse only to level to cover terminals for SMD.
10.10	Solder ability	J-STD-002	For both Leaded & SMD. Electrical Test not required. Magnification 50 X. Conditions: Leaded: Method A @ 235°C, category 3. SMD: a) Method B, 4 hrs @ 155°C dry heat @ 235°C b) Method B @ 215°C category 3. c) Method D category 3 @ 260°C.
10.11	Flammability	UL-94	V-0 or V-1 Acceptable
10.12	Board Flex	AEC Q200-005	60 sec minimum holding time.
10.13	Terminal Strength(SMD)	AEC Q200-006	-

11. Cautions for use**(1) Soldering upon mounting**

There is a possibility to influence product characteristics when Solder paste or conductive glue comes in contact with product lid or surface.

(2) When using mounting machine

Please minimize the shock when using mounting machine to avoid any excess stress to the product.

(3) Conformity of a circuit

We strongly recommend to make sure that Negative resistance (Gain) of IC is designed to be 10 times the ESR (Equivalent Series Resistance) of crystal unit.

12. Storage conditions

Please store product in below conditions, and use within 6 months.

Temperature +18 to +30°C, and Humidity of 20 to 70 % in the packaging condition.

13. Manufacturing location

Kyocera Corporation Yamagata Higashine Plant / Japan(Yamagata)

Kyocera Corporation Shiga Yohkaichi Plant / Japan(Shiga)

14. Quality Assurance

To be guaranteed by Kyocera Corporation Yamagata Higashine Plant Quality Assurance Division

15. Quality guarantee

In case when Kyocera Corporation rooted failure occurred within 1year after its delivery, substitute product will be arranged based on discussion. Quality guarantee of product after 1year of its delivery is waived.

16. Others

In case of any questions or opinions regarding the Specification, please have it in written manner within 45 days after issued date.